# **IGBT - Field Stop II**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop II Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. The IGBT is well suited for UPS and solar applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

#### **Features**

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Soft Fast Reverse Recovery Diode
- Optimized for High Speed Switching
- 10 µs Short Circuit Capability
- These are Pb-Free Devices

#### **Typical Applications**

- Solar Inverter
- Uninterruptible Power Inverter Supplies (UPS)
- Welding

#### **ABSOLUTE MAXIMUM RATINGS**

| Rating  | Symbol           | Value       | Unit |
|---|------------------|-------------|------|
| Collector-emitter voltage   | V <sub>CES</sub> | 1200        | V    |
| Collector current @ Tc = 25°C @ Tc = 100°C  | l <sub>C</sub>   | 80<br>40    | A    |
| Pulsed collector current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>                                 | I <sub>CM</sub>  | 200         | Α    |
| Diode forward current<br>@ Tc = 25°C<br>@ Tc = 100°C  | I <sub>F</sub>   | 80<br>40    | A    |
| Diode pulsed current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>                                     | I <sub>FM</sub>  | 200         | А    |
| Gate-emitter voltage<br>Transient gate-emitter voltage<br>$(T_{pulse} = 5 \mu s, D < 0.10)$               | V <sub>GE</sub>  | ±20<br>±30  | V    |
| Power Dissipation @ Tc = 25°C @ Tc = 100°C  | P <sub>D</sub>   | 535<br>267  | W    |
| Short Circuit Withstand Time $V_{GE} = 15 \text{ V}, V_{CE} = 500 \text{ V}, T_J \le 150^{\circ}\text{C}$ | T <sub>SC</sub>  | 10          | μs   |
| Operating junction temperature range  | TJ               | -55 to +175 | °C   |
| Storage temperature range   | T <sub>stg</sub> | -55 to +175 | °C   |
| Lead temperature for soldering, 1/8" from case for 5 seconds  | T <sub>SLD</sub> | 260         | °C   |

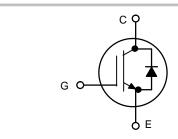
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

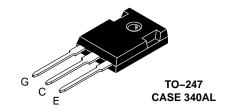


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40 A, 1200 V V<sub>CEsat</sub> = 2.0 V E<sub>off</sub> = 1.10 mJ





#### **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

#### **ORDERING INFORMATION**

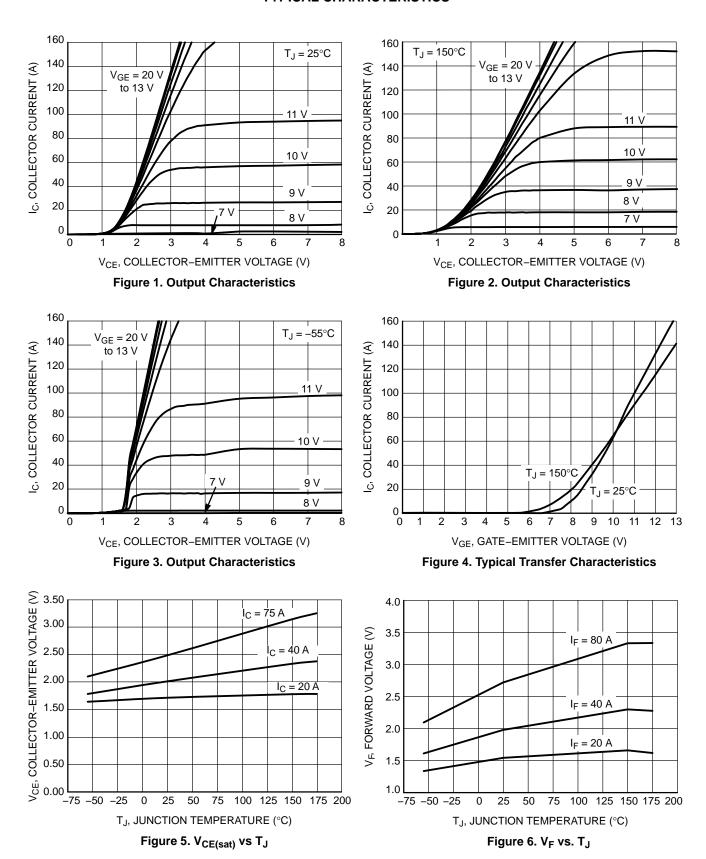
| Device          | Package             | Shipping        |
|-----------------|---------------------|-----------------|
| NGTB40N120FL2WG | TO-247<br>(Pb-Free) | 30 Units / Rail |

#### THERMAL CHARACTERISTICS

| Rating   | Symbol          | Value | Unit |
|--|-----------------|-------|------|
| Thermal resistance junction–to–case, for IGBT  | $R_{\theta JC}$ | 0.28  | °C/W |
| Thermal resistance junction–to–case, for Diode | $R_{\theta JC}$ | 0.5   | °C/W |
| Thermal resistance junction-to-ambient         | $R_{\theta JA}$ | 40    | °C/W |

| Parameter   | Test Conditions  | Symbol               | Min    | Тур          | Max      | Unit |
|---|--|----------------------|--------|--------------|----------|------|
| STATIC CHARACTERISTIC   |  |                      |        |              |          |      |
| Collector–emitter breakdown voltage, gate–emitter short–circuited   | $V_{GE} = 0 \text{ V, } I_{C} = 500  \mu\text{A}$  | V <sub>(BR)CES</sub> | 1200   | -            | -        | V    |
| Collector-emitter saturation voltage                                | V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A<br>V <sub>GE</sub> = 15 V, I <sub>C</sub> = 40 A, T <sub>J</sub> = 175°C     | V <sub>CEsat</sub>   | _      | 2.00<br>2.40 | 2.40     | V    |
| Gate-emitter threshold voltage                                      | $V_{GE} = V_{CE}, I_{C} = 400 \mu A$   | V <sub>GE(th)</sub>  | 4.5    | 5.5          | 6.5      | V    |
| Collector-emitter cut-off current, gate-<br>emitter short-circuited | V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V<br>V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V, T <sub>J =</sub> 175°C | I <sub>CES</sub>     | -<br>- | _<br>_       | 0.1<br>2 | mA   |
| Gate leakage current, collector–emitter short–circuited             | V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V   | I <sub>GES</sub>     | -      | _            | 200      | nA   |
|   |  |                      |        |              |          |      |
| Input capacitance   |  | C <sub>ies</sub>     | _      | 7385         | _        | pF   |
| Output capacitance  | $V_{CE} = 20 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$   | C <sub>oes</sub>     | _      | 230          | _        |      |
| Reverse transfer capacitance  | 1  | C <sub>res</sub>     | _      | 140          | _        |      |
| Gate charge total   |  | $Q_g$                | _      | 313          | _        | nC   |
| Gate to emitter charge  | $V_{CE} = 600 \text{ V}, I_{C} = 40 \text{ A}, V_{GE} = 15 \text{ V}$  | Q <sub>ge</sub>      | _      | 61           | _        |      |
| Gate to collector charge  | 1  | Q <sub>gc</sub>      | -      | 151          | -        |      |
| SWITCHING CHARACTERISTIC, INDUC                                     | TIVE LOAD  |                      |        |              |          |      |
| Turn-on delay time  |  | t <sub>d(on)</sub>   | _      | 116          | _        | ns   |
| Rise time   | T <sub>J</sub> = 25°C<br>V <sub>CC</sub> = 600 V, I <sub>C</sub> = 40 A  | t <sub>r</sub>       | _      | 42           | _        |      |
| Turn-off delay time   |  | t <sub>d(off)</sub>  | _      | 286          | _        |      |
| Fall time   |  | t <sub>f</sub>       | _      | 121          | _        |      |
| Turn-on switching loss  | $V_{GE} = 0 \text{ V/ } 15 \text{V}$   | E <sub>on</sub>      | _      | 3.4          | _        | mJ   |
| Turn-off switching loss   | T <sub>J</sub> = 25°C<br>$V_{CC} = 600 \text{ V, } I_{C} = 40 \text{ A}$<br>$R_{0} = 10 \Omega$                            | E <sub>off</sub>     | _      | 1.1          | _        |      |
| Total switching loss  |  | E <sub>ts</sub>      | _      | 4.5          | _        |      |
| Turn-on delay time  |  | t <sub>d(on)</sub>   | _      | 111          | _        | ns   |
| Rise time   | T <sub>J</sub> = 175°C   | t <sub>r</sub>       | _      | 43           | _        |      |
| Turn-off delay time   |  | t <sub>d(off)</sub>  | _      | 304          | _        |      |
| Fall time   | $V_{CC} = 600 \text{ V}, I_{C} = 40 \text{ A}$   | t <sub>f</sub>       | _      | 260          | _        |      |
| Turn-on switching loss  | $V_{GE} = 0 \text{ V/ } 15 \text{ V}$  | E <sub>on</sub>      | _      | 4.4          | _        | mJ   |
| Turn-off switching loss   | 1  | E <sub>off</sub>     | -      | 2.5          | _        |      |
| Total switching loss  | 1  | E <sub>ts</sub>      | -      | 6.9          | _        |      |
| DIODE CHARACTERISTIC  | •  | •                    |        |              |          |      |
| Forward voltage   | V <sub>GE</sub> = 0 V, I <sub>F</sub> = 40 A<br>V <sub>GE</sub> = 0 V, I <sub>F</sub> = 50 A, T <sub>J</sub> = 175°C       | V <sub>F</sub>       | -<br>- | 2.00<br>2.30 | 2.60     | V    |
| Reverse recovery time   | T <sub>J</sub> = 25°C  | t <sub>rr</sub>      | _      | 240          | _        | ns   |
| Reverse recovery charge   | $I_F = 40 \text{ Å}, V_R = 400 \text{ V}$<br>$di_F/dt = 200 \text{ A/}\mu\text{s}$   | Q <sub>rr</sub>      | _      | 2.5          | _        | μς   |
| Reverse recovery current  | αι <sub>Γ</sub> /αι – 200 Α/μδ   | I <sub>rrm</sub>     | _      | 18           | _        | Α    |
| Reverse recovery time   | T <sub>J</sub> = 175°C   | t <sub>rr</sub>      | _      | 392          | _        | ns   |
| Reverse recovery charge   | $I_F = 40 \text{ A}, V_R = 400 \text{ V}$<br>$di_F/dt = 200 \text{ A/}\mu\text{s}$   | Q <sub>rr</sub>      | _      | 5.36         | _        | μC   |
| Reverse recovery current  | αιμ/αι = 200 Α/μδ  | I <sub>rrm</sub>     | _      | 25.80        | _        | A    |

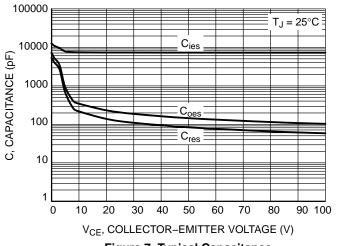
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



#### TYPICAL CHARACTERISTICS

70

60



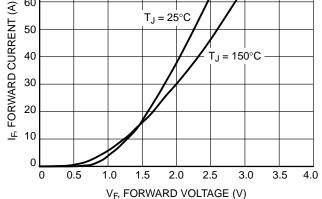
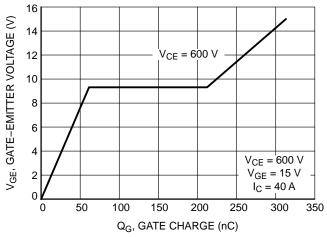


Figure 7. Typical Capacitance

Figure 8. Diode Forward Characteristics



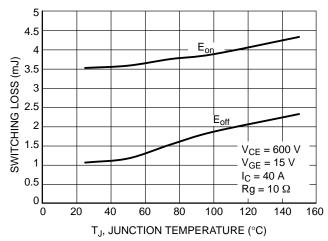
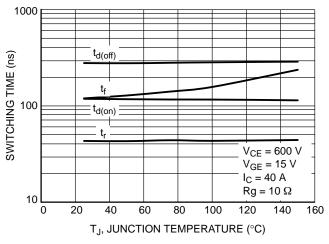


Figure 9. Typical Gate Charge

Figure 10. Switching Loss vs. Temperature



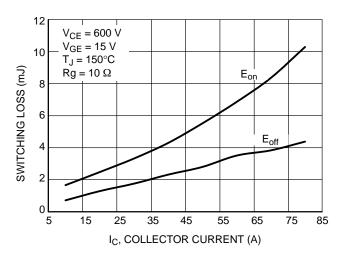


Figure 11. Switching Time vs. Temperature

Figure 12. Switching Loss vs. I<sub>C</sub>

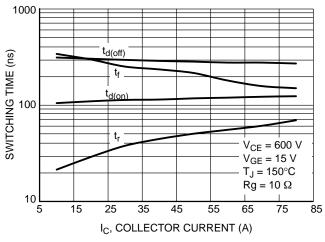


Figure 13. Switching Time vs. I<sub>C</sub>

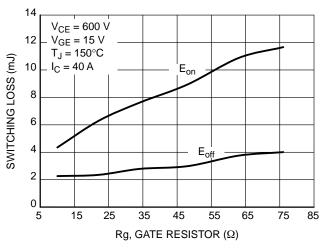


Figure 14. Switching Loss vs. Rg

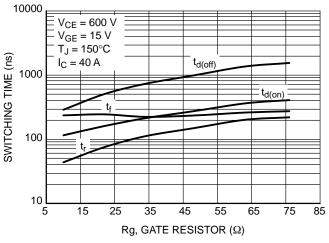


Figure 15. Switching Time vs. Rg

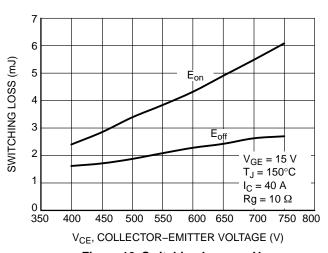


Figure 16. Switching Loss vs. V<sub>CE</sub>

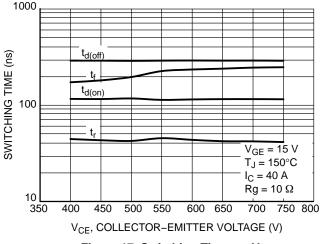


Figure 17. Switching Time vs. V<sub>CE</sub>

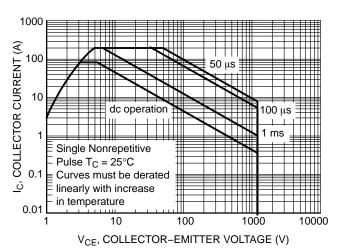


Figure 18. Safe Operating Area

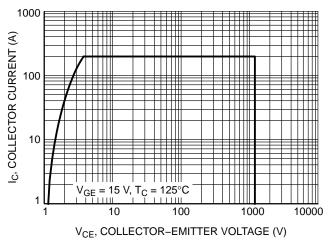


Figure 19. Reverse Bias Safe Operating Area

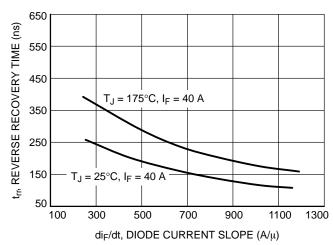


Figure 20.  $t_{rr}$  vs.  $di_F/dt$  ( $V_R = 400 V$ )

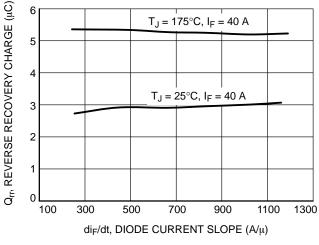


Figure 21.  $Q_{rr}$  vs.  $di_F/dt$  ( $V_R = 400 V$ )

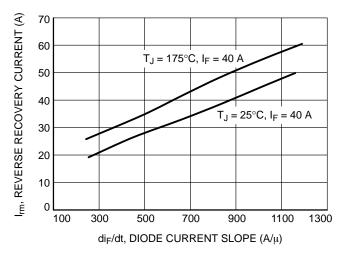


Figure 22.  $I_{rm}$  vs.  $di_F/dt$  ( $V_R = 400 \text{ V}$ )

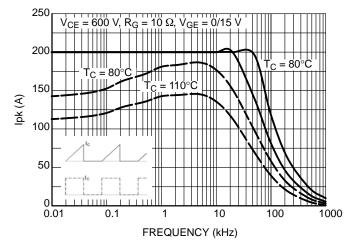


Figure 23. Collector Current vs. Switching Frequency

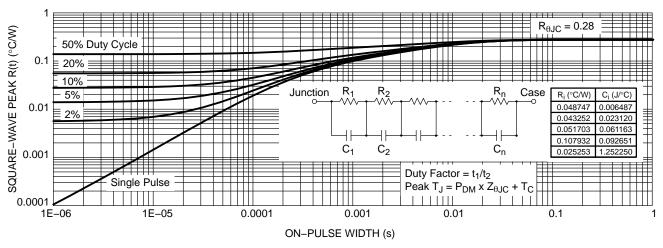


Figure 24. IGBT Transient Thermal Impedance

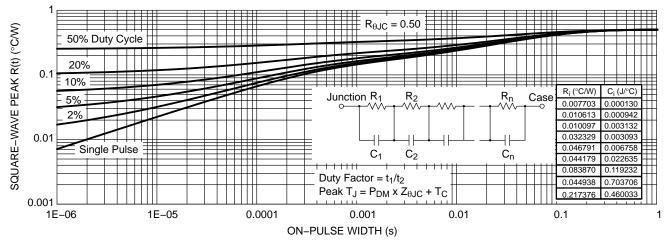


Figure 25. Diode Transient Thermal Impedance

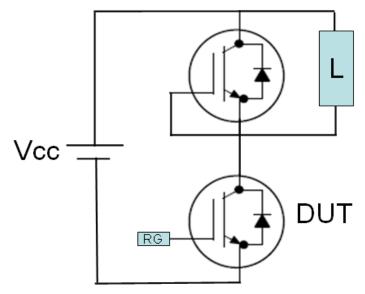


Figure 26. Test Circuit for Switching Characteristics

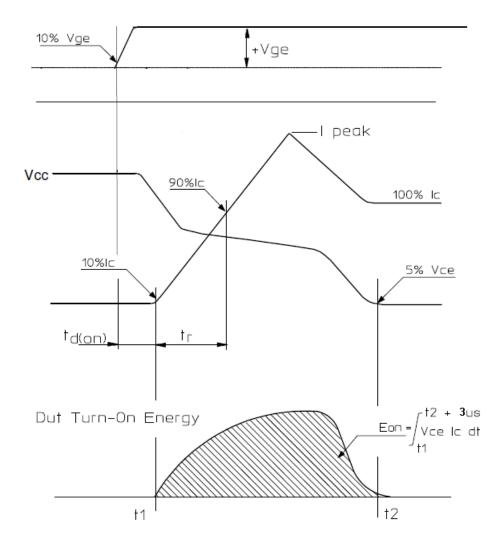


Figure 27. Definition of Turn On Waveform

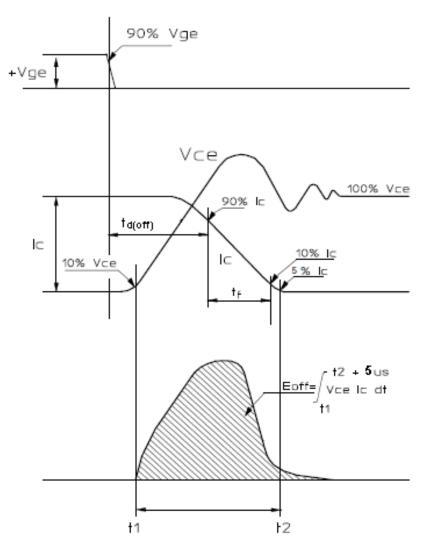
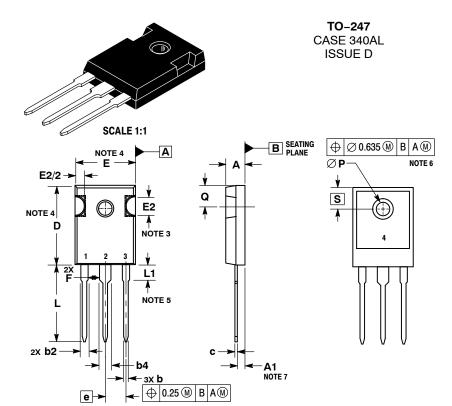


Figure 28. Definition of Turn Off Waveform



**DATE 17 MAR 2017** 

- NOTES:

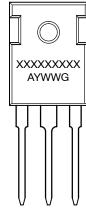
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. SLOT REQUIRED, NOTCH MAY BE ROUNDED.

  - DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH.
    MOLD FLASH SHALL NOT EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY
  - LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY
- ©P SHALL HAVE A MAXIMUM DRAFT ANGLE OF 1.5° TO THE TOP OF THE PART WITH A MAXIMUM DIAMETER OF 3.91.

  DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED

|     | MILLIMETERS |       |  |  |
|-----|-------------|-------|--|--|
| DIM | MIN         | MAX   |  |  |
| Α   | 4.70        | 5.30  |  |  |
| A1  | 2.20        | 2.60  |  |  |
| b   | 1.07        | 1.33  |  |  |
| b2  | 1.65        | 2.35  |  |  |
| b4  | 2.60        | 3.40  |  |  |
| С   | 0.45        | 0.68  |  |  |
| D   | 20.80       | 21.34 |  |  |
| Е   | 15.50       | 16.25 |  |  |
| E2  | 4.32        | 5.49  |  |  |
| е   | 5.45 BSC    |       |  |  |
| F   | 2.655       |       |  |  |
| L   | 19.80       | 20.80 |  |  |
| L1  | 3.81        | 4.32  |  |  |
| P   | 3.55        | 3.65  |  |  |
| Q   | 5.40        | 6.20  |  |  |
| S   | 6.15 BSC    |       |  |  |

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code Α = Assembly Location

Υ = Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.

|                              | DESCRIPTION: |             | Printed Versions are uncontrolled except when stamped CONTROLLED                                 | PAGE 1 OF 1 |  |
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